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Supplementary Information

Perovskite Single Crystal SCLC Measurements Prediction Using Machine Learning Model

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SCLC measurements:

We have calculated the Resistivity and Conductivity of devices by applying Ohm's Law (eq. 1) to I-V curves, which has been measured using the solar simulator and Keithley 2400.

V = IR.....(1) Resistance has been calculated by fitting the I-V curve of SCLC data, following the steps below.

 $R = \frac{V}{I}$

Dividing the area (A) in the above equation.

$$\frac{IR}{A} = \frac{V}{A}$$
$$JR = \frac{V}{A}$$
$$\log J + \log R = \log V - \log A$$

 $\log J = \log V - \log A - \log R \log J = \log V - (\log A + \log R)$ (2)

Which is in the form of

y = mx + cResistance (R) has been calculated by considering the intercept of *log J vs log V* of SCLC data. Subsequently, compared both equations and calculated the Rvalue followed by resistivity (ρ) by adding resulted R values in the below equation.

$$R = \rho \frac{d}{A}$$

d is the thickness of the device, ρ is resistivity, and A is the area. Conductivity (σ) is the reciprocal of resistivity (ρ).